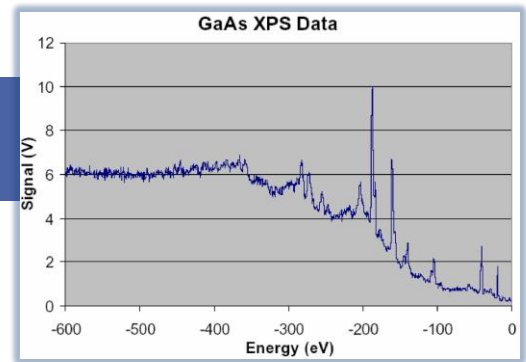# k-Space Associates, Inc.

# kSA 400 Auger/XPS Plug-In

Acquire & Analyze AES and XPS Data Directly from your kSA 400!

AES and XPS are both powerful techniques for surface analysis, relying on material-specific photoelectron energy signatures from either electron (AES) or X-ray (XPS) induced photoelectron emission. The Auger/XPS Plug-In for the kSA 400 provides complete computer control of the energy of the analyzer, stepping through a user-specified range of energies at a user-specified resolution (via a 12-bit D/A channel). The user may also specify the sampling number, scan rate, and number of scans. During data acquisition, which may be externally triggered, the photoelectron signal is analyzed via 16-bit analog input channel at each energy. Data is displayed in real-time during acquisition and all data is stored to a k-Space .kdt file upon completion. All data can be exported to standard file formats, including .xls and .txt.

Features

- Auger/XPS acquisition mode runs directly from your kSA 400 software!

- User-specified delay between acquisitions allows Auger/XPS electronics to stabilize at each energy value before reading the input signal

- Simple software, using standard kSA 400 interface, makes acquiring Auger/XPS energy-dependent data easy and fast

- Easily calibrate the system so the Auger power supply corresponds with the electron gun power supply; sets the gain and offset of the Input/Output boards for Auger/XPS

Simple Software and Interface
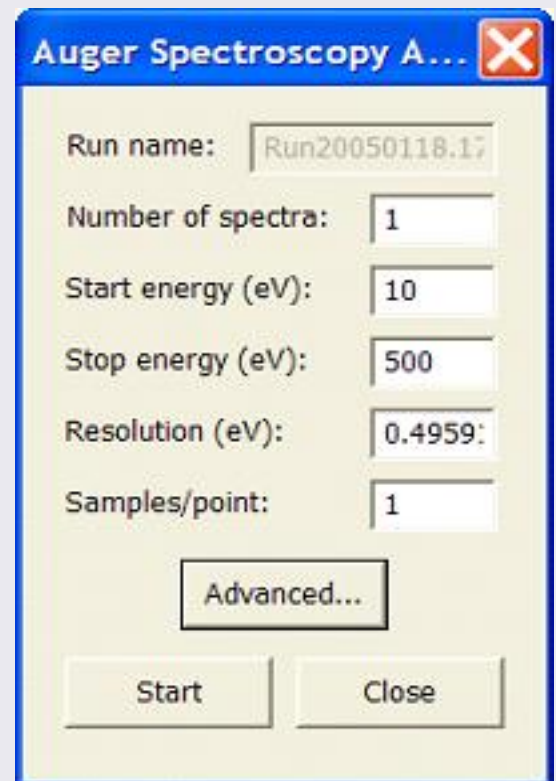
Your partner in thin film metrology

k-Space Associates, Inc., is a leading supplier to the surface science and thin-film technology industries. Since 1992, we've delivered the most advanced thin-film metrology tools and software thanks to close collaboration with our worldwide customer base.